

**Figure 5-11**  
Properties of an equilibrium p-n junction: (a) isolated, neutral regions of p-type and n-type material and energy bands for the isolated regions; (b) junction, showing space charge in the transition region  $W$ , the resulting electric field  $\mathcal{E}$  and contact potential  $V_0$ , and the separation of the energy bands; (c) directions of the four components of particle flow within the transition region, and the resulting current directions.

## Expression for Contact Potential

In equilibrium,  $J_p = J_n = 0$ .

$$\Rightarrow J_p = q\mu_p P \vec{E} - qD_p \frac{dP}{dx} = 0$$

$$\Rightarrow q\mu_p P \vec{E} = qD_p \frac{dP}{dx} \quad [\text{drift current} = \text{diffusion current}]$$

$$\Rightarrow -\frac{\mu_p}{D_p} dV(x) = \frac{dP(x)}{P(x)} \quad \left[ \because \vec{E}(x) = -\frac{dV(x)}{dx} \right]$$

$$\Rightarrow -\frac{q}{RT} \int_{V_p}^{V_n} dV(x) = \int_{P_{p0}}^{P_{n0}} \frac{dP(x)}{P(x)} \quad \left[ \frac{D_p}{\mu_p} = \frac{D_n}{\mu_n} = \frac{RT}{q} \right]$$

$$\Rightarrow -\frac{q}{RT} (V_n - V_p) = \ln \frac{P_{p0}}{P_{n0}}$$

$$\Rightarrow V_0 (\text{Contact potential}) \equiv V_n - V_p = \frac{RT}{q} \ln \frac{P_{p0}}{P_{n0}}$$

$$\textcircled{1} \Rightarrow P_{p0} = P_{n0} e^{\frac{qV_0}{RT}}$$

$$\text{Similarly, } n_{p0} = n_{n0} e^{-\frac{qV_0}{RT}}$$

$$\textcircled{2} \quad P_{p0} = N_A \quad \text{and} \quad P_{n0} = \frac{n_i^2}{N_D}$$

$$\therefore V_0 = \frac{RT}{q} \ln \frac{N_A N_D}{n_i^2}$$

$$\textcircled{3} \quad \frac{P_{p0}}{P_{n0}} = e^{\frac{qV_0}{RT}} = \frac{N_V e^{-(E_F - E_{vp})/RT}}{N_V e^{-(E_F - E_{vn})/RT}}$$

$$\Rightarrow e^{\frac{qV_0}{RT}} = e^{(E_{vp} - E_{vn})/RT}$$

$$\Rightarrow qV_0 = E_{vp} - E_{vn}$$

# Electric-field and potential distribution in a p-n junction diode

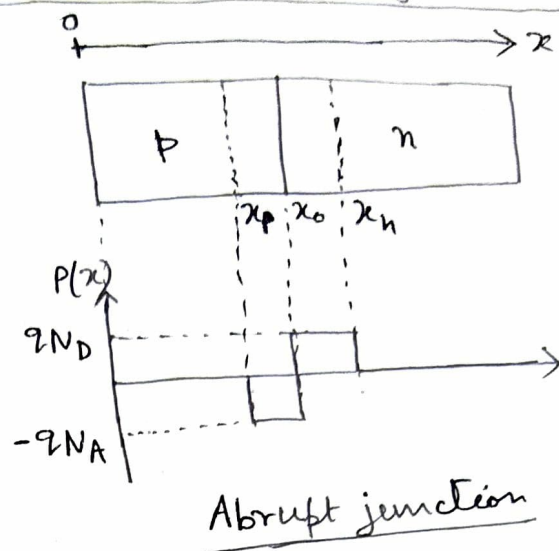
$$\rho(x) = q(N_D - N_A + p - n)$$

$$\rho(x) = 0 \text{ for } 0 \leq x \leq x_p$$

$$= -qN_A \text{ for } x_p < x < x_0$$

$$= qN_D \text{ for } x_0 < x < x_n$$

$$= 0 \text{ for } x \geq x_n$$



Poisson's equation:  $\frac{d^2 \phi(x)}{dx^2} = -\frac{\rho(x)}{\epsilon}$

$$\Rightarrow \frac{d^2 \phi_p(x)}{dx^2} = \frac{qN_A}{\epsilon_s} \text{ for } x_p < x < x_0 \dots (1)$$

$$\& \frac{d^2 \phi_n(x)}{dx^2} = -\frac{qN_D}{\epsilon_s} \text{ for } x_0 < x < x_n \dots (2)$$

Boundary conditions:

$$\phi_p(x_0) = \phi_n(x_0) \dots (3)$$

$$\phi_p(x) = 0 \text{ for } x \leq x_p \dots (4)$$

$$\phi_n(x) = V_0 - V \text{ for } x \geq x_n \dots (5)$$

considering applied potential  $-V$  to the n-side

$$\frac{d\phi_p(x_0)}{dx} = \frac{d\phi_n(x_0)}{dx} \dots (6)$$

$$\frac{d\phi_p(x)}{dx} = 0 \text{ for } x \leq x_p \dots (7)$$

$$\& \frac{d\phi_n(x)}{dx} = 0 \text{ for } x \geq x_n \dots (8)$$

Integrating eq. (1) and applying eq. (7), we get

$$\boxed{\frac{d\phi_p(x)}{dx} = \frac{qN_A}{\epsilon_s} (x - x_p) \dots (9) \text{ for } x_p < x < x_0}$$

Similarly, integrating eq. (2) and applying eq. (8),

we get

$$\boxed{\frac{d\phi_n(x)}{dx} = \frac{qN_D}{\epsilon_s} (x_n - x) \dots (10) \text{ for } x_0 < x < x_n}$$

$$* \vec{E}(x) = -\frac{d\phi(x)}{dx}$$

Integrating eq.(9) and applying eq.(1), we get

$$\boxed{\phi_p(x) = \frac{q N_A}{2 \epsilon_s} (x - x_p)^2} \dots (11) \text{ for } x_p < x < x_0$$

similarly, integrating eq.(10) and applying eq.(5),

we get  $\boxed{\phi_n(x) = -\frac{q N_D}{2 \epsilon_s} (x_n - x)^2 + (V_0 - V)} \dots (12) \text{ for } x_0 < x < x_n$

Applying eq.(6), one obtains  $N_A (x_0 - x_p) = N_D (x_n - x_0) \dots (13)$

& applying eq.(6);  $\frac{q N_A}{2 \epsilon_s} (x_0 - x_p)^2 = (V_0 - V) - \frac{q N_D}{2 \epsilon_s} (x_n - x_0)^2 \dots (14)$

From (13),  $x_0 - x_p = \frac{N_D}{N_A} (x_n - x_0)$

$$\Rightarrow (x_n - x_0) + (x_0 - x_p) = (x_n - x_0) + \frac{N_D}{N_A} (x_n - x_0)$$

$$\Rightarrow x_n - x_p = \left(1 + \frac{N_D}{N_A}\right) (x_n - x_0)$$

$$\Rightarrow x_n - x_0 = \frac{N_A}{N_A + N_D} \cdot W \dots (15)$$

similarly,  $x_0 - x_p = \frac{N_D}{N_A + N_D} \cdot W \dots (16)$

From (14);  $V_0 - V = \frac{q N_A}{2 \epsilon_s} (x_0 - x_p)^2 + \frac{q N_D}{2 \epsilon_s} (x_n - x_0)^2$

using (15) & (16);  $V_0 - V = \frac{q}{2 \epsilon_s} \left[ N_A \cdot \frac{N_D^2}{(N_A + N_D)^2} \cdot W + N_D \cdot \frac{N_A^2}{(N_A + N_D)^2} \cdot W \right]$

$$\Rightarrow V_0 - V = \frac{q}{2 \epsilon_s} \cdot \frac{N_A N_D}{(N_A + N_D)} \cdot W^2$$

$$\Rightarrow \boxed{W = \left[ \frac{2 \epsilon_s}{q} \left( \frac{1}{N_A} + \frac{1}{N_D} \right) (V_0 - V) \right]^{1/2}} \dots (17)$$

\*  $V_0 - V$  is the potential difference across the junction



Now  $|Q^+| = qA(x_n - x_0) \cdot N_D$  &  $|Q^-| = qA(x_0 - x_p) \cdot N_A$

$\therefore Q = |Q^+| = |Q^-|$  [by eq. (13)]

$= qA(x_n - x_0)N_D = qAN_D \cdot \frac{N_A}{N_A + N_D} \cdot W$  [by eq. (15)]

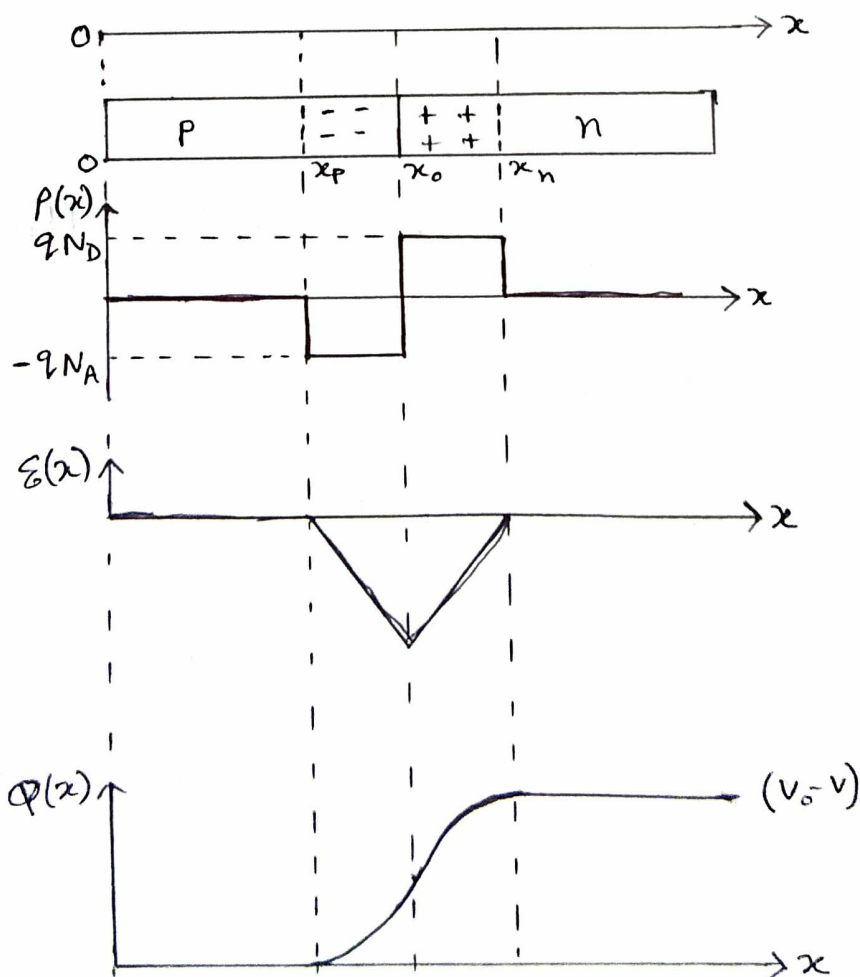
$= qA \frac{N_A N_D}{N_A + N_D} \left[ \frac{2\epsilon_s}{q} \cdot \frac{N_A + N_D}{N_A N_D} \cdot (V_0 - V) \right]^{1/2}$  [by (17)]

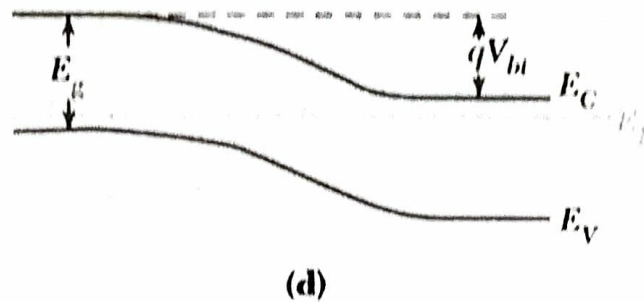
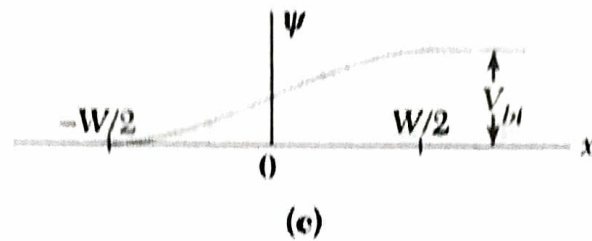
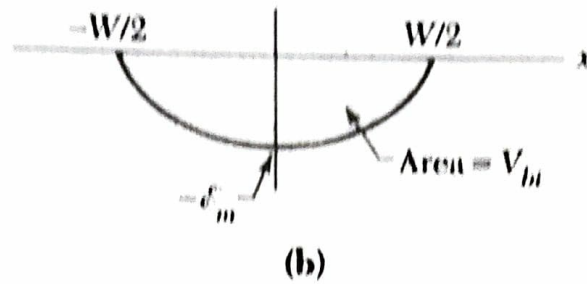
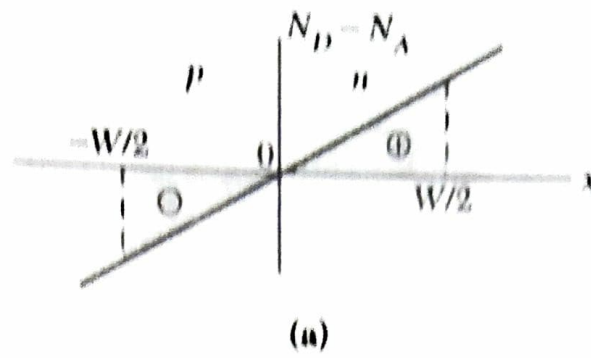
$= A \left[ 2\epsilon_s q \frac{N_A N_D}{N_A + N_D} \right]^{1/2} (V_0 - V)^{1/2}$

$\therefore C_j = \left| \frac{dQ}{dV} \right| = \left| A \left( 2\epsilon_s q \frac{N_A N_D}{N_A + N_D} \right)^{1/2} \cdot \frac{1}{2} (V_0 - V)^{-1/2} \cdot (-1) \right|$

$= A \left[ \frac{\epsilon_s q}{2} \left( \frac{N_A N_D}{N_A + N_D} \right) \right]^{1/2} (V_0 - V)^{-1/2}$

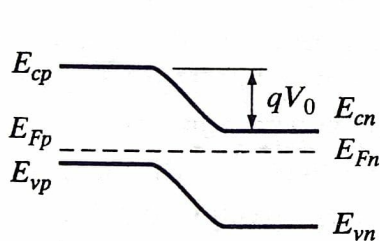
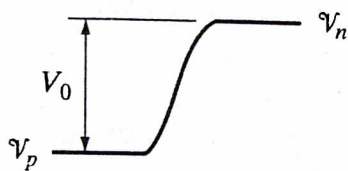
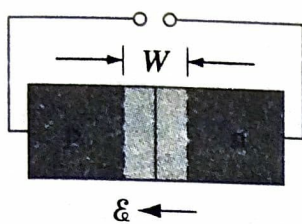
$\Rightarrow C_j = \frac{\epsilon_s A}{W}$



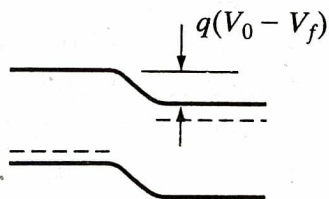
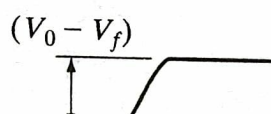
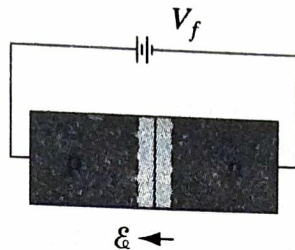


**Fig. 9 Linearly graded junction in thermal equilibrium. (a) Impurity distribution. (b) Electric field distribution. (c) Potential distribution. (d) Energy band diagram.**

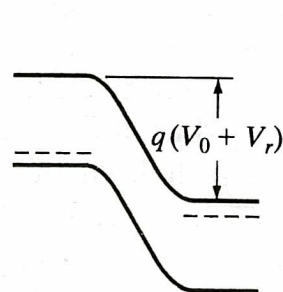
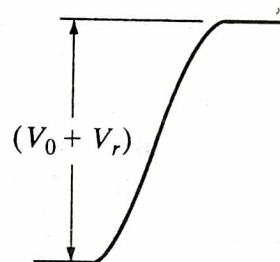
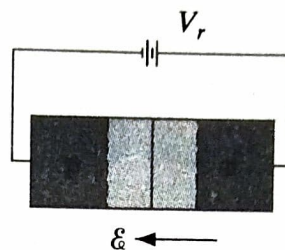
(a)  
Equilibrium  
( $V = 0$ )



(b)  
Forward bias  
( $V = V_f$ )



(c)  
Reverse bias  
( $V = -V_r$ )



**Figure 5-13**  
Effects of a bias at a p-n junction; transition region width and electric field, electrostatic potential, energy band diagram, and particle flow and current directions within  $W$  for (a) equilibrium, (b) forward bias, and (c) reverse bias.

Particle flow	Current
(1) $\rightarrow$	$\rightarrow$
(2) $\leftarrow$	$\leftarrow$
(3) $\leftarrow$ - -	- - $\rightarrow$
(4) - - $\rightarrow$	$\leftarrow$ - -

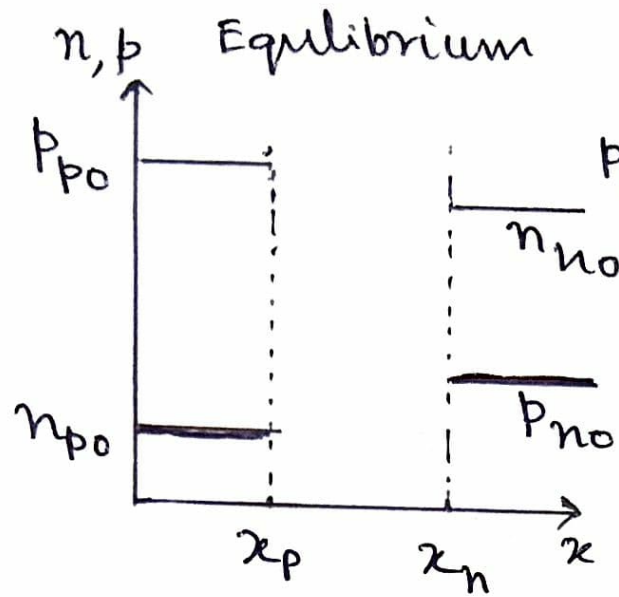
(1) Hole diffusion  
(2) Hole drift

Particle flow	Current
$\rightarrow$	$\rightarrow$
$\leftarrow$	$\leftarrow$
$\leftarrow$ - -	- - $\rightarrow$
- - $\rightarrow$	$\leftarrow$ - -

(3) Electron diffusion  
(4) Electron drift

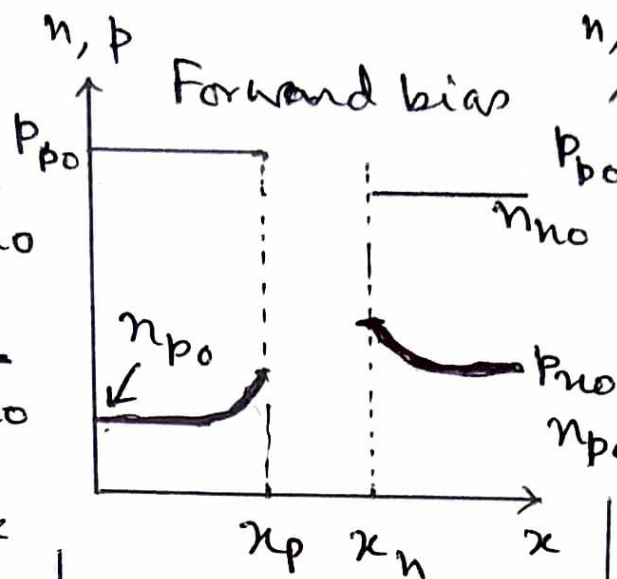
The *diffusion current* is composed of majority carrier electrons on the n side surmounting the potential energy barrier to diffuse to the p side, and

# Carrier Distribution



$$p_{po} = p_{no} e^{\frac{qV_o}{kT}}$$

$$n_{no} = n_{po} e^{\frac{qV_o}{kT}}$$



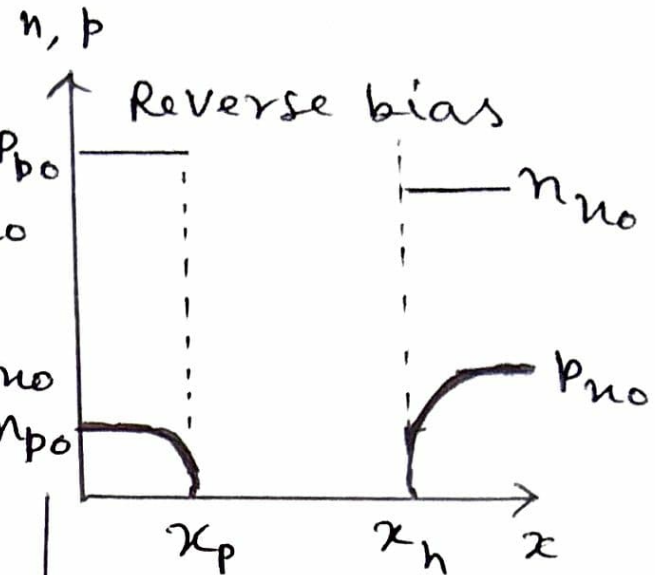
$$p_p(x_p) = p_n(x_n) e^{\frac{q(V_o - V)}{kT}}$$

$$\Rightarrow p_{po} = p_n(x_n) e^{\frac{q(V_o - V)}{kT}}$$

$$\Rightarrow p_n(x_n) = p_{po} e^{-\frac{qV_o}{kT}} e^{\frac{qV}{kT}}$$

$$\Rightarrow p_n(x_n) = p_{no} e^{\frac{qV}{kT}}$$

$$\& n_p(x_p) = n_{po} e^{\frac{qV}{kT}}$$



$$p_p(x_p) = p_n(x_n) e^{\frac{q(V_o + V)}{kT}}$$

$$\Rightarrow p_{po} = p_n(x_n) e^{q(V_o + V)/kT}$$

$$\Rightarrow p_n(x_n) = p_{po} e^{-\frac{qV_o}{kT}} e^{-\frac{qV}{kT}}$$

$$\Rightarrow p_n(x_n) = p_{no} e^{-\frac{qV}{kT}}$$

$$\& n_p(x_p) = n_{po} e^{-\frac{qV}{kT}}$$



#### IV characteristics of a p-n junction diode

From continuity equation;

$$\frac{\partial p(x,t)}{\partial t} = -\frac{1}{q} \frac{\partial J_p}{\partial x} - \frac{p-p_0}{\tau_p}$$

$$\& \frac{\partial n}{\partial t} = +\frac{1}{q} \frac{\partial J_n}{\partial x} - \frac{n-n_0}{\tau_n}$$

Outside the depletion region,  $\vec{E} = 0$

$$\therefore \frac{\partial J_p}{\partial x} = \frac{\partial}{\partial x} (pq\mu_p \vec{E} - qD_p \frac{\partial p}{\partial x}) = -qD_p \frac{\partial^2 p}{\partial x^2}$$

$$\text{Similarly, } \frac{\partial J_n}{\partial x} = qD_n \frac{\partial^2 n}{\partial x^2}$$

$$\text{Hence, } \frac{\partial p}{\partial t} = D_p \frac{\partial^2 p}{\partial x^2} - \frac{p-p_0}{\tau_p}$$

$$\& \frac{\partial n}{\partial t} = D_n \frac{\partial^2 n}{\partial x^2} - \frac{n-n_0}{\tau_n}$$

$$\text{In steady state, } \frac{\partial p}{\partial t} = \frac{\partial n}{\partial t} = 0.$$

$$\therefore \frac{d^2 p}{dx^2} = \frac{p-p_{n0}}{D_p \tau_p} \quad [\text{as } p_0 = p_{n0} \text{ in n-side}]$$

$$\& \frac{d^2 n}{dx^2} = \frac{n-n_{p0}}{D_n \tau_n} \quad [\text{as } n_0 = n_{p0} \text{ in p-side}]$$

$$\Rightarrow \frac{d^2 (p-p_{n0})}{dx^2} = \frac{p-p_{n0}}{L_p^2} \quad \left[ \text{where } L_p = \sqrt{D_p \tau_p} \text{ is called diffusion length of holes} \right]$$

$$\& \frac{d^2 (n-n_{p0})}{dx^2} = \frac{n-n_{p0}}{L_n^2} \quad \left[ L_n = \sqrt{D_n \tau_n}, \text{ diffusion length of electrons in p-side} \right]$$

Solution:  $p - p_{n0} = A e^{x/L_p} + B e^{-x/L_p}$

Since  $p = p_{n0}$  at  $x = x$ ,  $A = 0$

$\therefore p - p_{n0} = B e^{-x/L_p}$

Again  $p = p_n(x_n)$  at  $x = x_n$

$$\begin{aligned} \Rightarrow B &= [p_n(x_n) - p_{n0}] e^{\frac{x_n}{L_p}} \\ &= [p_{n0} e^{qV/kT} - p_{n0}] e^{x_n/L_p} \\ &= p_{n0} (e^{qV/kT} - 1) e^{x_n/L_p} \end{aligned}$$

$\therefore p - p_{n0} = p_{n0} (e^{qV/kT} - 1) e^{-(x-x_n)/L_p}$

$\delta p(x) = \Delta p_{x_n} e^{-(x-x_n)/L_p}$  where  $\delta p = p - p_{n0}$   
 &  $\Delta p_{x_n} = p_{n0} (e^{qV/kT} - 1)$

$$\begin{aligned} \therefore J_p &= -q D_p \frac{\partial p}{\partial x} = -q D_p p_{n0} (e^{qV/kT} - 1) e^{-(x-x_n)/L_p} \cdot \left(-\frac{1}{L_p}\right) \\ &= q \frac{D_p}{L_p} p_{n0} (e^{qV/kT} - 1) \cdot e^{-(x-x_n)/L_p} \end{aligned}$$

$\therefore J_p \Big|_{x=x_n} = q \frac{D_p}{L_p} p_{n0} (e^{qV/kT} - 1)$

Similarly, in the p-region;

$$n - n_{p0} = n_{p0} \left( e^{\frac{qV}{kT}} - 1 \right) e^{-(x_p-x)/L_n}$$

$$\therefore J_n(x) = q D_n \frac{\partial n}{\partial x} = q \frac{D_n}{L_n} n_{p0} \left( e^{\frac{qV}{kT}} - 1 \right) \cdot e^{-(x_p-x)/L_n}$$

$\therefore J_n \Big|_{x=x_p} = q \frac{D_n}{L_n} n_{p0} (e^{qV/kT} - 1)$

Considering no generation/recombination in the depletion region, both  $J_p$  &  $J_n$  are constant in the depletion region.

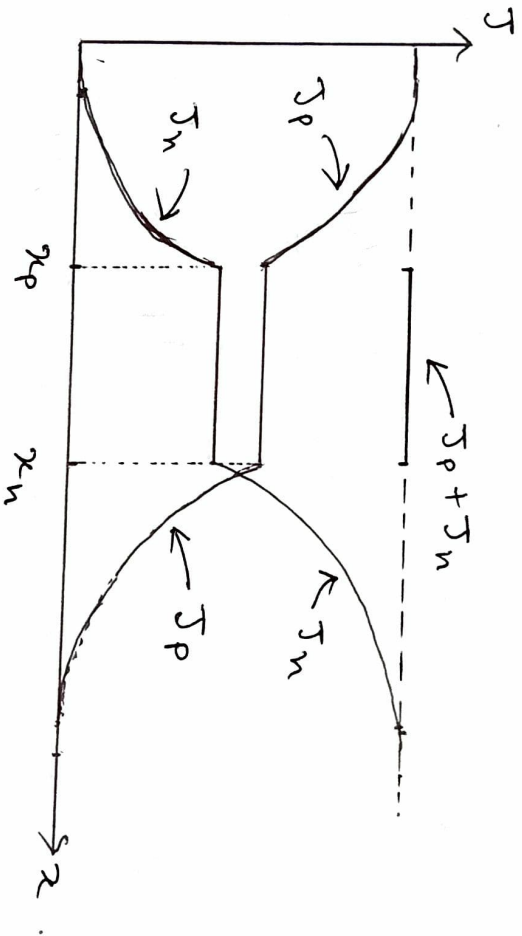
∴ Total current in the depletion region,

$$J = J_p + J_n = q \left( \frac{D_p}{L_p} p_{n0} + \frac{D_n}{L_n} n_{p0} \right) \left( e^{\frac{qV}{kT}} - 1 \right)$$

$$\Rightarrow J = J_0 \left( e^{\frac{qV}{kT}} - 1 \right)$$

$$\therefore I = J \times A = I_0 \left( e^{\frac{qV}{kT}} - 1 \right)$$

As current is continuous,  $J$  is constant everywhere.



For p-n junction, i.e.,  $N_A \gg N_D$

$$J = q \left( \frac{D_p}{L_p} \cdot \frac{n_i^2}{N_D} + \frac{D_n}{L_n} \cdot \frac{n_i^2}{N_A} \right) \left( e^{\frac{qV}{kT}} - 1 \right)$$

$$= q \frac{D_p}{L_p} \cdot \frac{n_i^2}{N_D} \left( e^{\frac{qV}{kT}} - 1 \right) = q \frac{D_p}{L_p} p_{n0} \left( e^{\frac{qV}{kT}} - 1 \right)$$

$$= q \frac{D_p}{L_p} N_V e^{-\frac{(E_F - E_{Vn})}{kT}} \cdot e^{\frac{qV}{kT}} \quad \left( \begin{array}{l} \text{neg. 1 in} \\ \text{forward bias} \end{array} \right)$$

$$= \frac{q D_p}{L_p} N_V e^{\frac{qV - (E_F - E_{Vn})}{kT}}$$

∴ Current is small if the forward bias is less than  $(E_F - E_{Vn})/q$ . The current increases rapidly if the forward bias is slightly higher than  $(E_F - E_{Vn})/q$ . This is the cut-in voltage, which is slightly less than bandgap value. For heavily doped p-side  $E_F = E_{VP} \Rightarrow E_F - E_{Vn} \approx E_{VP} - E_{Vn} = qV_0$

## Diffusion Capacitance

Considering  $p^+-n$  junction, total excess hole charge in the  $n$ -side,  $Q_p = qA \int_0^\infty \delta p(x) dx = qA \Delta p_{x_n} \int_0^\infty e^{-(x-x_n)/L_p} dx$   
 $= qAL_p \cdot \Delta p_{x_n} \approx qAL_p p_{n0} e^{qV/RT}$

$$\therefore C_s \equiv \frac{dQ_p}{dV} = \frac{q^2}{RT} AL_p p_{n0} e^{\frac{qV}{RT}} = \frac{q}{RT} \cdot Q_p = \frac{q}{RT} \cdot I \tau_p$$

$$\therefore C_s = \frac{dI}{dV} = \frac{q}{RT} \cdot I$$

## Temperature Dependence of IV characteristics

$$I = I_0 (e^{qV/RT} - 1); \quad I_0 \propto n_i^2 = AT^3 e^{-E_g/RT}$$

$$\left. \begin{aligned} \frac{dI_0}{dT} &\approx 0.8 \text{ for Si} \\ &\approx 1.1 \text{ for Ge} \end{aligned} \right\}$$

$I_0$  gets doubled for every  $10^\circ\text{C}$  rise in temperature for Si

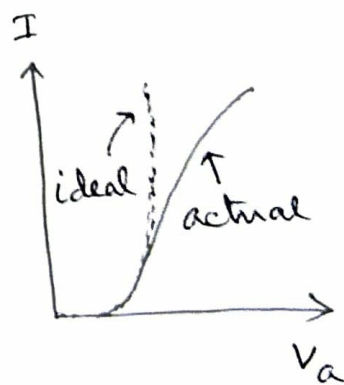
Also,  $I \propto e^{qV/RT}$  &  $\frac{dV}{dT} \approx -2.5 \text{ mV}/^\circ\text{C}$  for Si.

## Effects of Ohmic Loss

We assumed that the applied voltage appears entirely across the junction (i.e.,  $V_a = V_j$ ). This is valid in most cases as doping is fairly high ( $N_d$ , small  $\rho$ ) and area  $A$  is large compared to length  $l$ . For low doping, device may exhibit Ohmic effects, as

$$V_j = V_a - I [R_p(I) + R_n(I)]$$

$R_p$  &  $R_n$  are function of  $I$  because of conductivity modulation.





## Effects of Generation-Recombination in the depletion region

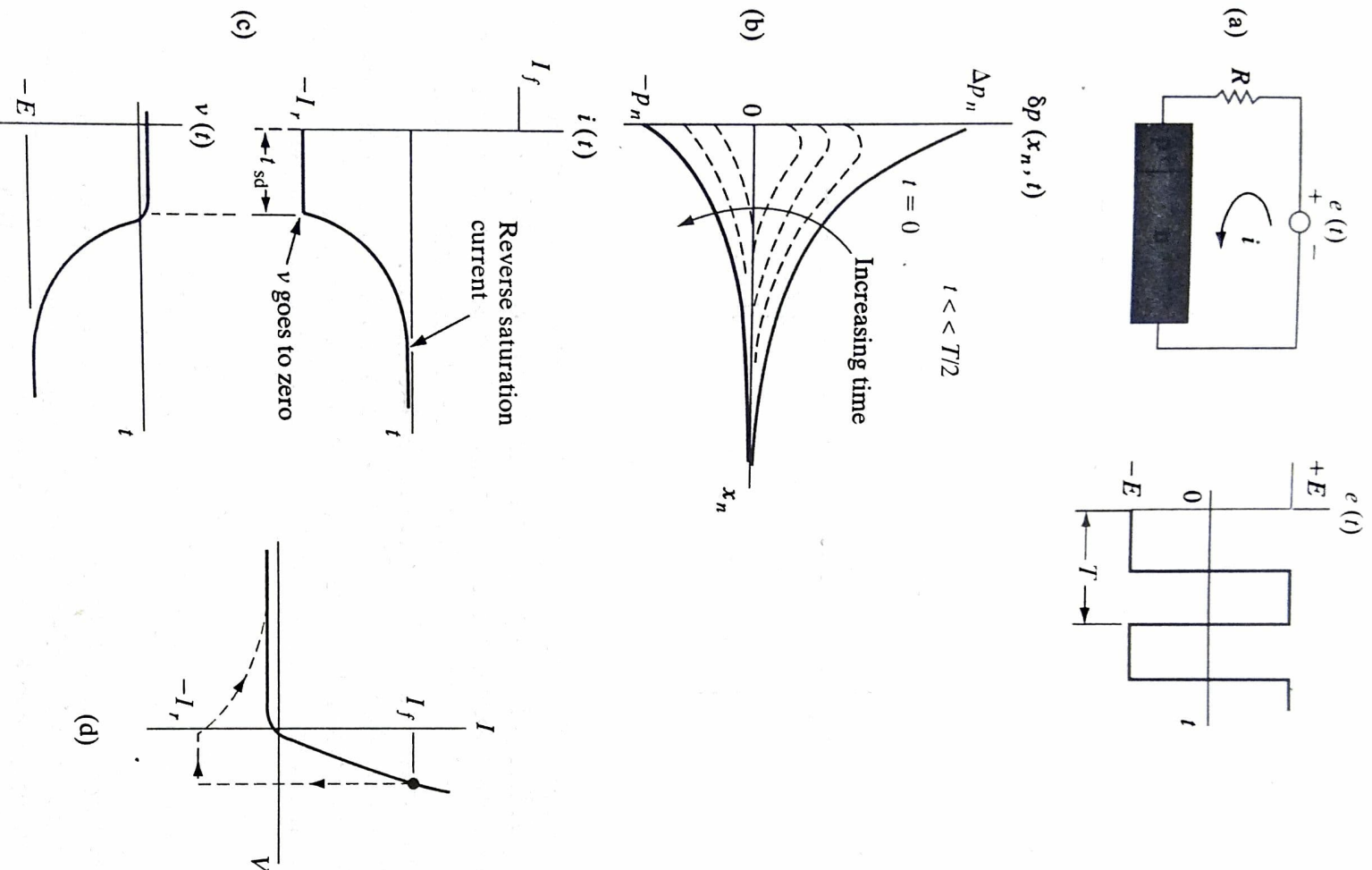
$$J = \underbrace{q \frac{D_p}{L_p} \cdot \frac{n_i^2}{N_D} \cdot e^{qV/RT}}_{\text{diffusion current}} + \underbrace{\frac{qWn_i}{2\tau_r} \cdot e^{qV/2RT}}_{\text{recombination current}}$$

$\tau_r$  is the effective recombination lifetime (indirect)

Overall  $J \propto e^{\frac{qV}{\eta RT}}$  ;  $\eta$  = ideality factor

$1 < \eta < 2$  ;  $\eta = 1$  when diffusion current dominates  
 $= 2$  " recombination " " }

Value of  $\eta$  (2) depends upon temperature (low),  
bandgap (wide) and applied bias (low).



**Figure 5-28**  
 Storage delay time in a  $p^+n$  diode: (a) circuit and input square wave; (b) hole distribution in the  $n$ -region as a function of time during the transient; (c) variation of current and voltage with time; (d) sketch of transient current and voltage on the device  $I$ - $V$  characteristic.

comes negative, the junction exhibits a negative voltage. Since the reverse-bias voltage of a junction can be large, the source voltage begins to divide between  $R$  and the junction. As time proceeds, the magnitude of the reverse current becomes smaller as more of  $-E$  appears across the reverse-biased junction, until finally the only current is the small reverse saturation current which is characteristic of the diode. The time  $t_{sd}$  required for the stored charge

**Figure 5-29**  
Effects of storage  
delay time on  
switching signal:  
(a) switching volt-  
age; (b) diode  
current.

